IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT: Gattiker DOCKET NO.: AUS920030653US1

SERIAL NO: (Not Yet Assigned) EXAMINER: (Not Yet Assigned)

FILED: (herewith) ART UNIT: (Not Yet Assigned)

TITLE: METHOD AND SYSTEM FOR ANALYZING QUIESCENT POWER PLANE

CURRENT (IDDQ) TEST DATA IN VERY-LARGE SCALE INTEGRATED (VLSI)

CIRCUITS

MAIL STOP PATENT APPLICATION COMMISSIONER FOR PATENTS P.O. BOX 1450 ALEXANDRIA, VA 22313-1450 Weiss, Moy & Harris, P.C. 4204 North Brown Avenue Scottsdale, AZ 85251-3989

Dear Sir:

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This Information Disclosure Statement is submitted in regards to the above-identified patent application. A PTO-SB/08 form is attached along with copies of the references cited therein.

No fee is believed to be required in connection with this Information Disclosure Statement. However, if there are any fees incurred by this transmittal, please deduct them from IBM Deposit Account NO. 09-0447.

Respectfully submitted,

Andrew M. Harris Reg. No. 42,638 (706) 782-9683

Weiss, Moy & Harris, P.C. 4204 North Brown Ave. Scottsdale, AZ 85251

PTO/SB/08A (04-03)

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		First Named Inventor	Gattiker	
	STATEMENT BY APPLICANT	Art Unit		
	(Use as many sheets as necessary)	Examiner Name		
$\overline{}$	Sheet 1 of 3	Attorney Docket Number	AUS920030653US1	

Examiner		Document Number	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where
Initials*		Number-Kind Code ^{2 (# known)}	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant Figures Appear
		^{US-} 6366108-B1	04-02-2002	Maxwell, et al.	
		^{US-} 6175244-B1	01-16-2001	Gattiker, et al.	
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FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages			
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STATEMENT BY APPLICANT				First Named Inventor	Gattiker	
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Sheet	2	of	3	Attorney Docket Number	AUS920030653US1	

		NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issunumber(s), publisher, city and/or country where published.			
		KRUSEMAN, ET AL. The Future of IDDQ Testing, IEEE International Test Conference Proceedings, 2001			
		THIBEAULT, Improving Delta-IDDQ-based Test Methods, IEEE International Test Conference Proceedings, 2000			
		MAXWELL,, ET AL. Current Ratios: A Self-Scaling Technique, IEEE International Test Conference Proceedings, 1999			
		GATTIKER,, ET AL. Current Signatures, IEEE VLSI Test Symposium Proceedings, 1996			
		OKUDA, Eigen-Signatures for Regularity-based IDDQ Testing, IEEE VLSI Test Symposium Proceedings, 2002			
		OKUDA, DECOUPLE: Defect Current Detection in Deep Sub-micron IDDQ, IEEE International Test Conference Proceedings, 2000			
		VARIYAM, Increasing the IDDQ Test Resolution Using Current Prediction, IEEE International Test Conference Proceedings, 2000			
		BERGMAN, ET AL., Improved IDDQ Testing With Empirical Linear Prediction, IEEE International Test Conference Proceedings, 2002			
		HENRY, ET AL., Burn-in Elimination of a High Volume Microprocessor Using IDDQ, IEEE International Test Conference Proceedings, 1996			
		NIGH, Application and Analysis of IDDQ Diagnostic Software, IEEE International Test Conference Proceedings, 1997			

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INF	ORMATION	DIS	CLOSURE	Filing Date		
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Sheet	3	of	3	Attorney Docket Number	AUS920030653US1	

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Examiner Initials*	No.1	the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
		LAVO, ET AL., Eliminating the Ouija Board: Automatic Thresholds and Probabilistic IDDQ Diagnosis, IEEE International Test Conference Proceedings, 1999	
		GATTIKER, Current Signatures for Integrated Circuit Test Strategy Advisor, Carnegie Mellon University, Ph.D. Dissertation	
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